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 Semiconductors Limited
 ISO/TS16949:2002
 FILE NO. A9273

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Reliability Test Summary

RTS No: 1174

Device Family: IC LNB
Packages: MSOP8, MSOP10, QFN1633085E, QFN1633, QFN1644, QFN2444, QSOP16, QSOP20, QSOP24, SO8
Date From: 13/10/2006
Date To: 04/09/2007

Environmental Trial Data

Trial Type	Specification	Lots	Tested	Failed	Cumulative Hours	% Failures
CLV (Autoclave)	JESD22-A102	4	180	0	17280	0.000%
CS (Cold Store)	JESD22-A119	2	90	0	90720	0.000%
HS (Hot Store)	JESD22-A103	3	135	0	136080	0.000%
RSHF (Resistance to Solder Heat Float)	JESD22-B106	3	135	0	135	0.000%
Solderability (Post Hot Store)	IEC68-2-20	2	90	0	90	0.000%
TC (Temperature Cycle Air to Air)	JESD22-A104	5	225	0	226800	0.000%
THB (Temperature Humidity + Bias)	JESD22-A101	3	135	0	136080	0.000%

Electrical Stress Trials

Electrical Trial Type: **HTOL (High Temperature Operating Life - JESD22-A108)**
 Service Temperature (Deg C): 55
 Ambient Temperature (Deg C): 125
 Activation Energy (eV): 0.9
 Confidence Level (%): 60

Actual Device Hours: 272160
 Equivalent Device Hours: 7.349E+07
 Lots: 6
 Devices Tested: 270
 Devices Failed: 0

Mean Time To Failure (Hours): 8.021E+07
 Failure Rate FITs: 12.4678
 Failure Rate %/1000 Hours: 1.247E-03

David Fitton
 Quality Engineer